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FORM PTO-1449	SERIAL NO. 09/775,172	ATTORNEY DOCKET NO. 3209.2.2
<b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b>	FILING DATE February 1, 2001	GROUP ART UNIT
(use several sheets if necessary)	APPLICANT(S): See-Wai Yip et al.	

**REFERENCE DESIGNATION**

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
AN	A1	5,982,898	11/09/1999	Hsu et al.	380/23	03/07/97
AN	A2	5,684,950	11/04/1997	Date et al.	395/187.01	09/23/96

EXAMINER	Andrew Nalven	DATE CONSIDERED	6/30/04
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



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FORM PTO-1449		SERIAL NO. 09/775,172	ATTORNEY DOCKET NO. 3209.2.2
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT  (use several sheets if necessary)		FILING DATE February 1, 2001	GROUP ART UNIT 2165
		APPLICANT(S): See-Wai Yip et al.	

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REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	TECHNOLOGY CENTER 2100 FILING DATE
AN	A1	5,745,574	04/28/1998	Muftic	380/23	12/15/1995
AN	A2	5,655,077	08/05/1997	Jones et al.	395/187.01	12/13/1994

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION	
						YES	NO
AN	A3	WO 00/10286	02/24/2000	JAPAN	H04L 9/32		X

EXAMINER Andrew Nalven	DATE CONSIDERED 6/30/09
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